

Search Notes

Application/Control No.

10/682,542

Examiner

X. L. Bautista

Applicant(s)/Patent under
Reexamination

WEE ET AL.

Art Unit

2179

SEARCHED

Class	Subclass	Date	Examiner
same as	prior search	12/23/2006	XB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search	12/23/2006	XB
Databases Searched: US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB		
Google Search		
IEEE Xplore Search		